

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1 (Currently Amended). A probe assembly for probing an electrical device, said probe assembly comprising:

- (a) a chuck having a first conductive member with a support surface suitable for supporting an electrical device; and
- (b) a second conductive member having a substantially planar surface spaced apart from, and opposed to, said support surface of said chuck, wherein said support surface is electrically interconnected to said second conductive member[.];
- (c) wherein said second conductive member is electrically interconnected to a test signal of said electrical device.

2 (Cancel).

3 (Original). The probe assembly of claim 1 wherein said first conductive member comprises a first plate, said second conductive member comprises a second plate, and wherein said second conductive member is spaced further distant from said electrical device than said first conductive member.

4 (Original). The probe assembly of claim 1 wherein said second conductive member comprises a second plate and is vertically spaced apart from said first conductive member.

5 (Previously presented). The probe assembly of claim 1 wherein said second conductive member is electrically interconnected to said support surface completely within an environmental chamber.

6 (Original). The probe assembly of claim 1 wherein said second conductive member is free from being supported by said chuck.

7 (Original). The probe assembly of claim 1 wherein said first conductive member is electrically interconnected to a first probe, wherein said second conductive member is electrically interconnected to a second probe.

8 (Original). The probe assembly of claim 1 wherein said first conductive member and said second conductive member are electrically interconnected to a first probe.

9 (Previously presented). The probe assembly of claim 1 wherein said first conductive member is electrically interconnected to a first probe and wherein said first probe is electrically interconnected to test instrumentation using a conductive element having a length, at least 50% of said length comprising a twisted pair of wires.

10 (Original). The probe assembly of claim 1 further comprising a detachable substantially closed loop member engageable with said first conductive member and said second conductive member, where said loop member includes a flexible member interconnecting said first conductive member and said second conductive member.